



NOTES

1. MATERIAL: UVFS
2. CLEAR APERTURE: 24 mmX34 mm
3. CUT-ON(CUT-OFF) WAVELENGTH: 785 nm
4. TRANSMITTED WAVEFRONT: $\lambda @ 633 \text{ nm}$
5. SURFACE QUALITY(S1, S2): 60/40(S/D)
6. SURFACE FLATNESS(S1, S2): $\lambda / 2 @ 632.8 \text{ nm}$
7. COATING(S1): FILTERING, 45° AOI
 $T_{\text{avg}} \geq 93\% @ 795-1155 \text{ nm}$
 $T_{\text{abs}} \geq 92\% @ 795-900 \text{ nm}$
 $R_{\text{abs}} \geq 90\% @ 784-786 \text{ nm}$
 $R_{\text{abs}} \geq 95\% @ 785 \text{ nm}$

DRAWING PROJECTION			LBTEK			
	NAME	DATE	RT785RDC-R			
DRAWN	JLIU	AUG./7st/25	RAMAN DICHOIC MIRROR L x W x H=36 mm x 25.5 mm x 1mm, 785 nm			
APPROVAL	WCHENG	AUG./7st/25	MATERIAL	WEIGHT	SCALE	REV
FOR INFORMATION ONLY NOT FOR MANUFACTURING PURPOSES			UVFS	2.2 g	2:1	A